

# **2SK2098-01MR**

## FUJI POWER MOSFET

# N-CHANNEL SILICON POWER MOSFET

# **FAP-III SERIES**

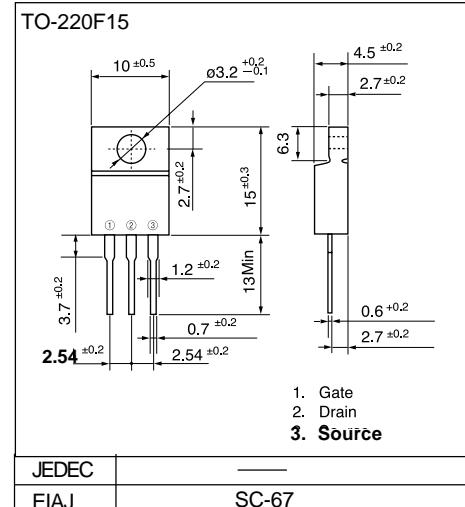
## ■ Features

- High current
  - Low on-resistance
  - No secondary breakdown
  - Low driving power
  - High forward Transconductance
  - Avalanche-proof

## ■ Applications

- Motor controllers
  - General purpose power amplifier
  - DC-DC converters

## ■ Outline Drawings

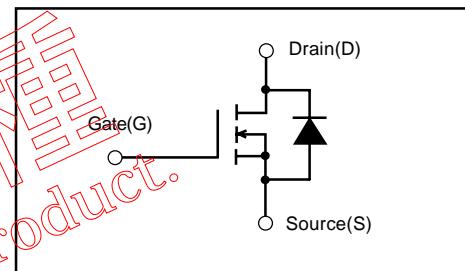


## ■ Maximum ratings and characteristics

- **Absolute maximum ratings (T<sub>c</sub>=25°C unless otherwise specified)**

Item	Symbol	Rating	Unit
Drain-source voltage	V <sub>DS</sub>	150	V
Continuous drain current	I <sub>D</sub>	20	A
Pulsed drain current	I <sub>D(puls)</sub>	80	A
Continuous reverse drain current	I <sub>DR</sub>	20	A
Gate-source peak voltage	V <sub>GS</sub>	±20	V
Max. power dissipation	P <sub>D</sub>	50	W
Operating and storage temperature range	T <sub>ch</sub> / T <sub>std</sub>	+150 / -55 to +150	°C

## ■ Equivalent circuit schematic



#### ● Electrical characteristics ( $T_c = 25^\circ\text{C}$ unless otherwise specified)

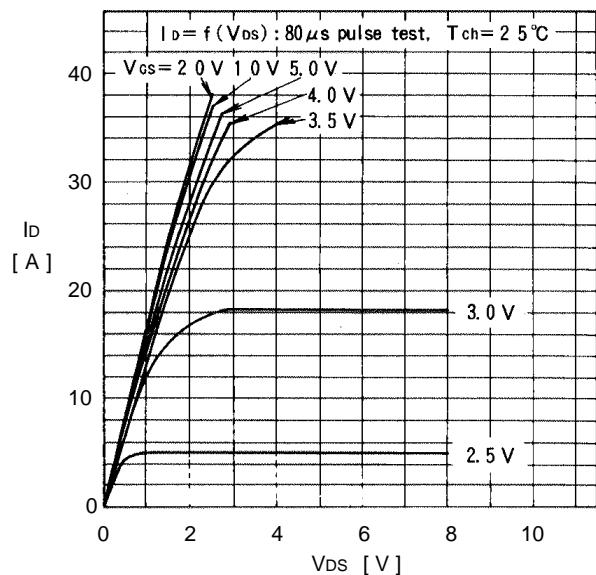
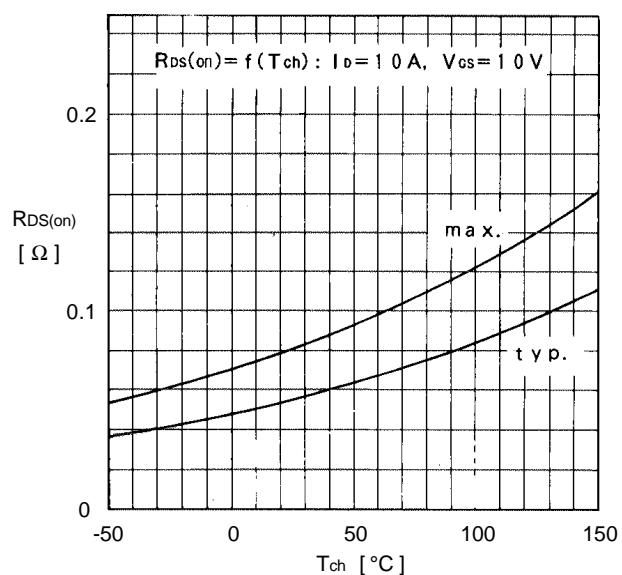
Item	Symbol	Test Conditions		Min.	Typ.	Max.	Units
Drain-source breakdown voltage	V <sub>BRDSS</sub>	I <sub>D</sub> =1mA V <sub>GS</sub> =0V		150			V
Gate threshold voltage	V <sub>GSOH</sub>	I <sub>D</sub> =1mA V <sub>DS</sub> =V <sub>GS</sub>		1.0	1.5	2.5	V
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =150V V <sub>GS</sub> =0V		T <sub>ch</sub> =25°C T <sub>ch</sub> =125°C	10 0.2	500 1.0	μA mA
Gate-source leakage current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V V <sub>DS</sub> =0V			10	100	nA
Drain-source on-state resistance	R <sub>DSS(on)</sub>	I <sub>D</sub> =10A		V <sub>GS</sub> =4V V <sub>GS</sub> =10V	0.065 0.055	0.100 0.080	Ω
Forward transconductance	g <sub>fs</sub>	I <sub>D</sub> =10A V <sub>DS</sub> =25V			10	20	
Input capacitance	C <sub>iss</sub>	V <sub>DS</sub> =25V V <sub>GS</sub> =0V f=1MHz			2300	3450	pF
Output capacitance	C <sub>oss</sub>				330	500	
Reverse transfer capacitance	C <sub>rss</sub>				150	230	
Turn-on time t <sub>on</sub> (t <sub>on</sub> =t <sub>d(on)</sub> +t <sub>r</sub> )	t <sub>d(on)</sub> t <sub>r</sub>	V <sub>CC</sub> =30V R <sub>G</sub> =25Ω I <sub>D</sub> =20A V <sub>GS</sub> =10V			15	25	ns
Turn-off time t <sub>off</sub> (t <sub>off</sub> =t <sub>d(off)</sub> +t <sub>f</sub> )	t <sub>d(off)</sub> t <sub>f</sub>				20	30	
Avalanche capability	I <sub>AV</sub>				450	700	
Diode forward on-voltage	V <sub>SD</sub>				100	150	
Reverse recovery time	t <sub>rr</sub>	I <sub>F</sub> =2xI <sub>DR</sub> V <sub>GS</sub> =0V T <sub>ch</sub> =25°C			20		A
Reverse recovery charge	Q <sub>rr</sub>				1.00	1.50	V
		I <sub>F</sub> =I <sub>DR</sub> V <sub>GS</sub> =0V			125		ns
		-di/dt=100A/μs T <sub>ch</sub> =25°C			0.6		μC

### ● Thermal characteristics

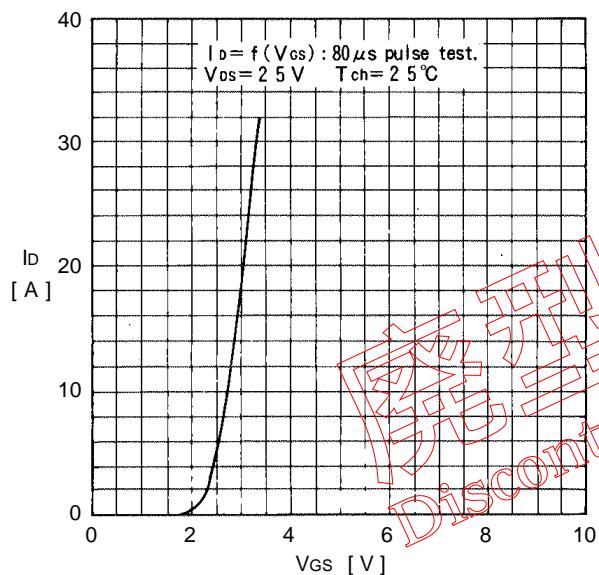
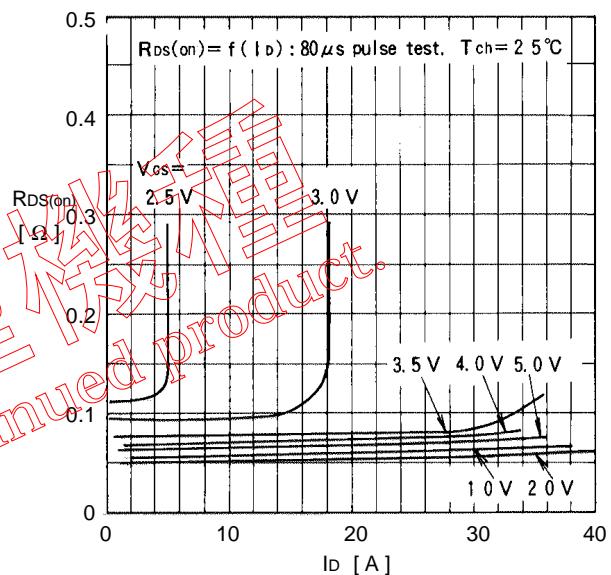
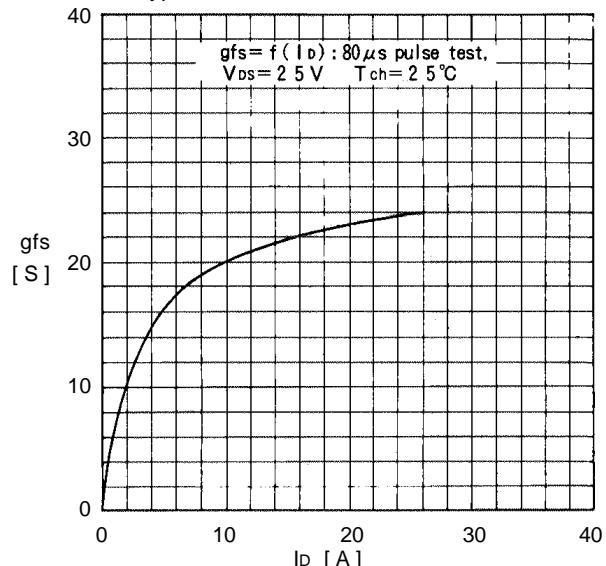
Item	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Thermal resistance	R <sub>th(ch-a)</sub>	channel to ambient			62.5	°C/W
	R <sub>th(ch-c)</sub>	channel to case			2.5	°C/W

## ■ Characteristics

Typical output characteristics

On state resistance vs.  $T_{ch}$ 

Typical transfer characteristics

Typical Drain-Source on state resistance vs.  $I_D$ Typical forward transconductance vs.  $I_D$ Gate threshold voltage vs.  $T_{ch}$ 